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|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/561,624 | | Applicant(s)/Patent Under Reexamination FABER ET AL. | |
| | Examiner YUN QIAN | | Art Unit 4162 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-5,266,355 | 11-1993 | Wernberg et al. | 427/248.1 |
| * | B | US-2004/0175949 | 09-2004 | Lee et al. | 438/691 |
| * | C | US-2003/0153088 | 08-2003 | DiMeo et al. | 436/113 |
| * | D | US-2002/0177685 | 11-2002 | Cook et al. | 528/271 |
| * | E | US-5,464,656 | 11-1995 | Verkade, John G. | 427/248.1 |
| * | F | US-6,124,427 | 09-2000 | Atwood, David Allan | 528/485 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|----------------|----------------------|
| | N | JP 09211314 | 01-1997 | Japan | Kawamura Hideo | F01N 3/24, 3/28, 7/1 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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